

<b>Notice of References Cited</b>	Application/Control No. 10/720,311	Applicant(s)/Patent Under Reexamination SUN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,924,204	08-2005	Tsai et al.	438/386
	B	US-2003/0082884	05-2003	Faltermeier et al.	438/387
	C	US-6,838,334	01-2005	Gluschenkov et al.	438/243
	D	US-6,451,662	09-2002	Chudzik et al.	438/386
	E	US-6,143,645	11-2000	Hsu et al.	438/627
	F	US-6,472,321	10-2002	Srinivasan et al.	438/680
	G	US-4,298,629	11-1981	Nozaki et al.	438/776
	H	US-6,534,376	03-2003	Tews, Helmut Horst	438/386
	I	US-6,828,185	12-2004	Lim et al.	438/216
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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